S	earch :	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/009,590	CHEN ET AL.	
Examiner -	Art Unit	
Anne R. Kubelik	1638	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH (INCLUDING SEAR		·)
	DATE	EXMR
See EASt search history	5/8/2006	ARK
See STN search notes	. 5/8/2006	ARK
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